



### The lateral PNP

Slower than vertical devices due to large base series resistance  $(r_{bb'})$  and base-to substrate capacitance



Lower early voltage  $(V_A)$ , due to non-optimal collector doping.

Larger than vertical devices for the same current capability

### The substrate PNP: compatible with standard CMOS n-well processes



BJT output characteristics



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BJT model in the forward active zone

$$I_{C} = I_{S} e^{\frac{V_{BE}}{V_{T}}} \left(1 + \frac{V_{CB}}{V_{A}}\right) \qquad V_{CB} = V_{CE} - V_{BE}$$
$$I_{B} = \frac{I_{C}}{\beta_{F}}$$

Sometimes this expression is used in order to refer to  $V_{BE}$  and  $V_{CE}$  as control voltages:

$$I_C \cong I_S e^{\frac{V_{BE}}{V_T}} \left(1 + \frac{V_{CE}}{V_A}\right)$$

For calculation of  $I_C$  and  $I_B$  in all operating zones (saturation, cut-off, forward active, reverse active) the Ebers-Moll model should be used.

# BJT: small signal model



BJT capacitances in forward active region (vertical npn)



# BJTs in Integrated Circuit: instance parameters



BJT sizing: Effect of the area parameter on the electrical parameters

Electrical effects of area parameter:

elemental BJT

elemental BJT with area specified as an instance parameter



## BJT sizing: Gummel plot and beta plot



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